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Application No. 10 054,911	Prepared by	N.H.	Tracking Number	05884460	
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a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449			
b. Applicant(s)	g. Disclaimer	I. Print Fig.	q. PTOL-85b			
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract			
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs			
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other			

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		"Design, Tolerance A Devices", Kerstin Wo	nalysis, and Fab orhoff et al., Jour	rication of nal of Lig	Silicon Oxynitride Based htwave Technology, Vol.	17, No. 8, Aug	ust 1999, pages	1401-1407.		
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